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| Sheet | 1 of 1 | | | GROUP | GROUP ART UNIT: 2838 EXAMI | | ER: R.B. Patel | | |
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| | | U.S. Patent Document | | | PATENT DOCUMENTS | Date of Publication or of issue | | | |
| Examiner's Initials | Cite No. | Number | | Kind Code | Name of Patentee or Applicant of Cited Document | | of Cited Document MM-DD-YYYY | | |
| | | T152002/1/2270 A | | | Kimura Katsuji | | 11-07-2002 | | |
| | US2002/163379 * | | | Kimura Katsuji | | 11-07-2002 | | | |
| | 5,821,807 • | | 7 • | | Brooks | | 10-12-1998 | | |
| | | | | | | | | | |
| - J | ļ | 5,126,653 * | | | Ganesan et al | 06-30-1992 | | | |
| <u> </u> | <u> </u> | <u> </u> | | FORFIC | ON PATENT DOCUMENTS | | | | |
| Examiner's Initials | Cite No. | Foreign Patent Document | | | Name of Patentee or Applicant of Cited | | Date of | | • |
| | | Office/ Country | Number | Kind Code | Document (not necessary) | | Publication of Cited Document MM-DD-YYYY | , , | |
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| | <u> </u> | <u> </u> | | <u> </u> | | | <u>'</u> | | |
| | | | | | PATENT LITERATURE DOCU | | | , | |
| Examiner's Initials | . Cite No | Thook magazine journal serial symposium catalog etc.), date, relevant page(S), volume-issue number(S), | | | | | | | |
| | International Search Report | | | | | | | | |
| | | Dos Reis Filho, Carlos A. et al, "Elements for a monolithically integrated rotation imbalance detector", IEEE, Vol. 2, June 9, 2003, pp. 897-900 | | | | | | | _ |
| | | | | | | | | | |
| Bakker, M.A.P. Pertijs, et al, "A high-accuracy temperature sensor with second-order curvature correction and digital bus interface", IEEE, Vol. 1, May 6, 2001, pp. 368-371. | | | | | | | | | <u></u> |
| <u> </u> | <u> </u> | | | | | | | | L |
| EXAMINER: | | 7) | | • | DATE CONSIDERED | : | | | |
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^{*}a copy of this reference is not provided